

Constant Intermooulation Loci Measure for Power Devices Using H.P. 8510 Network Analyzer

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A method of characterization for the IMD behaviour of power FET is presented. Curves with constant IMD and constant gain lie on the Gamma/sub L/ locus have been obtained in order to select the appropriate load for the FET and to maximize the device linearity. Examples to correlate the validity of this approach referred to the other one for the designing of amplifier chains are presented too.

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